

L Number	Hits	Search Text	DB
32	1	257/686.ccls. and (replacement adj chip) and defective	US-PGPUB; EPO; JPO
34	1	257/686.ccls. and (replacement adj chip) and defective	US-PGPUB; EPO; JPO
33	23	257/777.ccls. and defective	US-PGPUB; EPO; JPO
31	1	257/777.ccls. and (replacement adj chip) and defective	US-PGPUB; EPO; JPO
35	19	stack and (circuit adj block) and semiconductor and defective	US-PGPUB; EPO; JPO

L Number	Hits	Search Text	DB
17	0	257/686.ccls. and (defective adj circuit adj block)	USPAT
18	0	257/686.ccls. and (defective adj circuit adj blocks)	USPAT
19	6	257/686.ccls. and (defective adj circuit)	USPAT
20	35	semiconductor and stack and (defective adj circuit)	USPAT
21	36	stack and (circuit adj block) and semiconductor and defective	USPAT
23	0	257/685.ccls. and (defective adj circuit adj block)	USPAT
22	5	257/777.ccls. and (defective adj circuit)	USPAT
24	77	257/777.ccls. and defective	USPAT
25	1	257/777.ccls. and (replacement adj chip) and defective	USPAT
27	1	257/685.ccls. and (replacement adj chip) and defective	USPAT
26	1	257/686.ccls. and (replacement adj chip) and defective	USPAT